

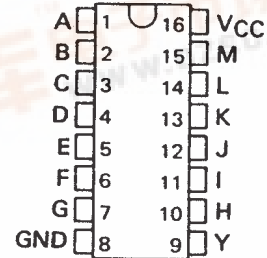
- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

These devices contain a single 13-input NAND gate.

The SN54133 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74133 is characterized for operation from 0°C to 70°C.

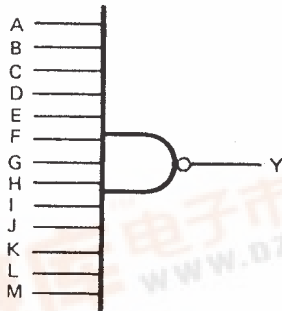
SN54S133 . . . J OR W PACKAGE
SN74S133 . . . D OR N PACKAGE
 (TOP VIEW)



FUNCTION TABLE

INPUTS A THRU M	OUTPUT Y
All inputs H	L
One or more inputs L	H

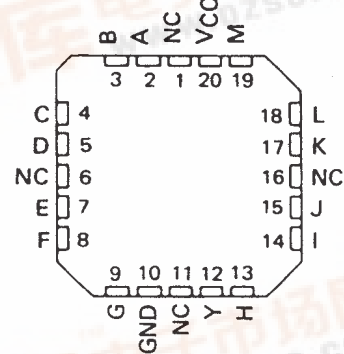
logic diagram



positive logic

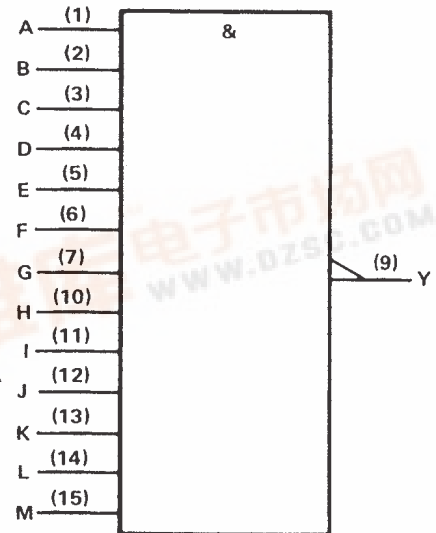
$$Y = \overline{A \cdot B \cdot C \cdot D \cdot E \cdot F \cdot G \cdot H \cdot I \cdot J \cdot K \cdot L \cdot M} \text{ or } \overline{A + B + C + D + E + F + G + H + I + J + K + L + M}$$

SN54S133 . . . FK PACKAGE
 (TOP VIEW)



NC - No internal connection

logic symbol†



†This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

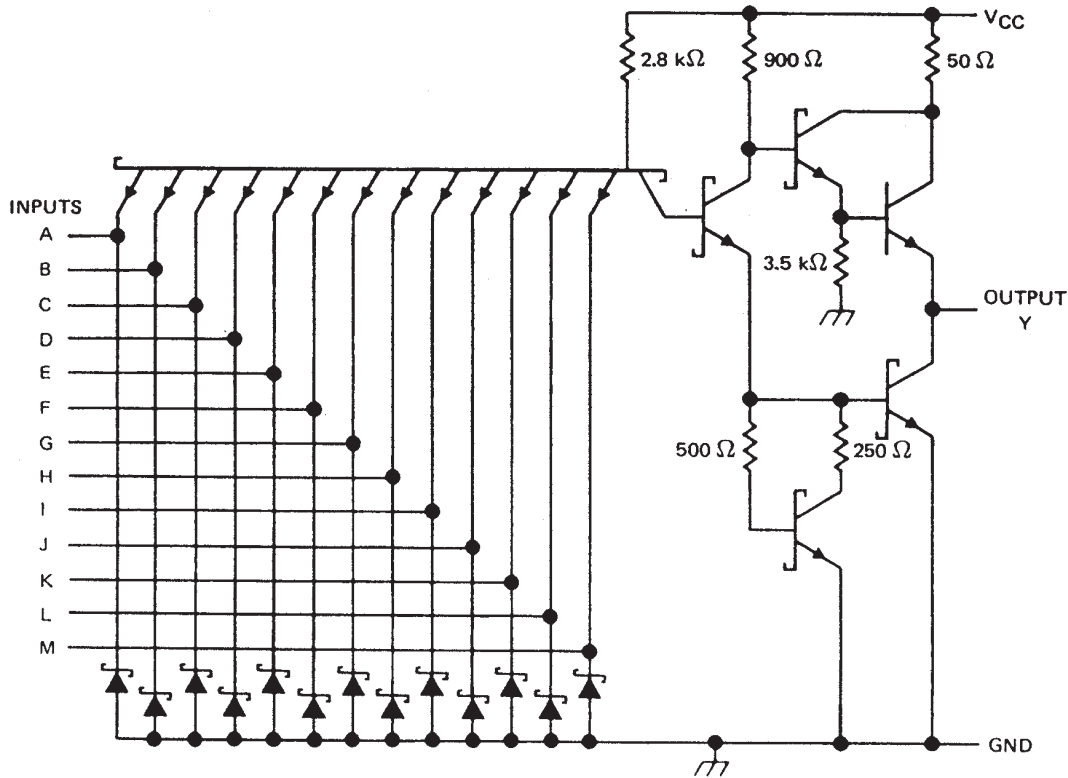
Pin numbers shown are for D, J, N, and W packages.



SN54S133, SN74S133 13-INPUT POSITIVE-NAND GATES

SDLS202 – DECEMBER 1983 – REVISED MARCH 1988

'S133



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage	5.5 V
Operating free-air temperature range: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

SN54S133, SN74S133 13-INPUT POSITIVE-NAND GATES

SDLS202 – DECEMBER 1983 – REVISED MARCH 1988

recommended operating conditions

	SN54S133			SN74S133			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.8			0.8	V
I _{OH} High-level output current			-1			-1	mA
I _{OL} Low-level output current			20			20	mA
T _A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN54S133			SN74S133			UNIT
		MIN	TYP ‡	MAX	MIN	TYP ‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = -18 mA			-1.2			-1.2	V
V _{OH}	V _{CC} = MIN, V _{IL} = 0.8 V, I _{OH} = -1 mA	2.5	3.4		2.7	3.4		V
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 20 mA			0.5			0.5	V
I _I	V _{CC} = MAX, V _I = 5.5 V			1			1	mA
I _{IH}	V _{CC} = MAX, V _I = 2.7 V			50			50	μA
I _{IL}	V _{CC} = MAX, V _I = 0.5 V			-2			-2	mA
I _{OS} §	V _{CC} = MAX	-40		-100	-40		-100	mA
I _{CCH}	V _{CC} = MAX, V _I = 0 V		3	5		3	5	mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V		5.5	10		5.5	10	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	Any	Y	R _L = 280 Ω, C _L = 15 pF	4	6		ns
t _{PHL}				4.5	7		ns
t _{PLH}			R _L = 280 Ω, C _L = 50 pF	5.5			ns
t _{PHL}				6.5			ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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